## DAMIC at SNOLAB Excess

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#### Outline

- Charge-coupled devices (CCDs).
- CCD detector response.
- DAMIC at SNOLAB.
- Dark Matter (DM) / WIMP Search.
- The Event **Excess**.
- Upgrade DAMIC at SNOLAB to investigate.

## Charge coupled device



Standard fabrication in semiconductor industry and easy cryogenics (~100 K).



Device is "exposed," collecting charge until user commands readout

Readout can be slow / non-destructive : low noise (few e-)

Silicon band-gap: 1.2 eV Mean energy for 1 e-h pair: 3.8 eV

#### **CCD** readout



## Charge measurement





#### **Detector response**

Mn  $K_{\alpha}$  from front and back



## Nuclear recoil response

- Detector response calibrated with 24 keV neutrons from <sup>9</sup>Be(γ,n) reaction.
- By comparing data and Monte Carlo spectra, ionization efficiency was measured to be lower than predicted by Lindhard model.
- Also validates diffusion model at low energies.





#### **SNOLAB Installation**



## Dark Matter Search

- 7 CCDs (40 g target mass) collected 11
  kg-day of data over >1 year.
- We compare the observed spectrum of events with a model for our background.
- We measure an excess of 17.1 ± 7.6 events above background model.





#### **Event selection**

No clustering in *masked* regions.

For every candidate cluster, we perform a likelihood ratio test between the white-noise only and white-noise + Gaussian hypothesis. The resulting test statistic ∆LL is used to reject noise.



## **Background model**

- Consider *E* and  $\sigma_x$  for final events >6 keV<sub>ee</sub> (no DM signal).
- Generate Monte Carlo templates: start from radioactive decays in detector components + apply detector response.
- Fit CCD data with templates constrained by measured contamination.



## Partial charge collection

- CCD backside contact in highly-doped in-situ doped polysilicon (ISDP).
- ▶ Phosphorous (P) in ISDP layer diffuses a microns into the CCD bulk.
- At intermediate P concentrations some of the ionization charge recombines → partial charge collection.
- ► Causes spectral distortion for decays on CCD backside, esp. <sup>210</sup>Pb.
- We parametrize spectral distortion from simulation and include it as "free" component in our fit to the DM search region.





#### Excess

- Excess of 17.1 ± 7.6 events.
- Exponential decay spectrum with  $\varepsilon$  = 67 ± 37 eV<sub>ee</sub>.
- Fit prefers signal + background over background-only with *p* value 2.2 x 10<sup>-4</sup>.

0.200





#### **Event distributions**



## Systematics

- Events really look like they are in the bulk:
- 1) Compare backside and bulk signal distributions.
- 2) Perform signal extraction after removing single-pixel events (preferentially from the front surface): Consistent exponential excess with *p* value 2.6 x 10<sup>-3</sup>.
- Statistically, data is well-behaved: no statistically significant features in the spectrum besides the low energy excess.



- No known background or detector response hypothesis to explain the excess.
- Known unknowns: unidentified noise source? imperfect surface background response model?

# DAMIC Upgrade

- Install DAMIC-M and SENSEI skipper CCDs in DAMIC cryostat.
- ▶ Two 6kx4k CCDs and four 1kx6k CCDs (27 grams).
- Same background environment, much better energy and depth reconstruction.
- Does the excess persist?







#### Thank you!